



# Alliance Semiconductor Corporation

## RELIABILITY REPORT

### High Temperature Operating Life (HTOL)

Part #	# Lots	Package	Qty.	Stress VCC	Lifetest Duration	Hours@ 125C	FIT@ 60%	MTTF Hrs. @55C
AS7C33512PFS32A	3	TQFP	405	3.6V	1000Hrs	398,008	3.42	2.92E+08

Assumptions: 0.7 ae Assumed for  
Failure Rates calculated to + 40C

Formula's used: TAF=  $\exp[Ea/k (1/Tuse - 1/Tstress)]$   
VAF =  $\exp[B/Gox(Vs - Vop)]$   
FIT =  $2n C2 / (2 \times TAF \times VAF \times \#Device\ Hours) \times 1E9$